

Docket No. 240416US0DIV

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Masakazu KANECHIKA, et al.

SERIAL NO: New Application

FILED: Herewith

FOR: METHOD OF MANUFACTURING SEMICONDUCTOR DEVICE AND SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449 and Japanese Office Action. Copies of the references listed on the Japanese Office Action are attached herewith. All other listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

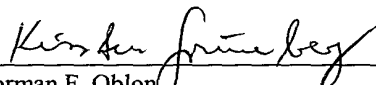


22850

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Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.


Norman F. Oblon

Registration No. 24,618

Kirsten A. Grüneberg, Ph.D.

Registration No. 47,297

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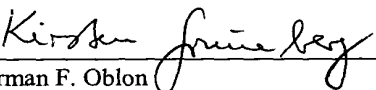
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REQUEST FOR PRIORITY

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

- ☒ Full benefit of the filing date of U.S. Application Serial Number 09/420,524, filed 10/18/99, is claimed pursuant to the provisions of 35 U.S.C. §120.
- ☐ Full benefit of the filing date(s) of U.S. Provisional Application(s) is claimed pursuant to the provisions of 35 U.S.C. §119(e):
- | <u>Application No.</u> | <u>Date Filed</u> |
|--|-------------------|
| <input checked="" type="checkbox"/> Applicants claim any right to priority from any earlier filed applications to which they may be entitled pursuant to the provisions of 35 U.S.C. §119, as noted below. | |

In the matter of the above-identified application for patent, notice is hereby given that the applicants claim as priority:

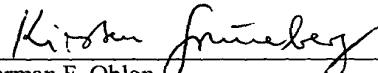
<u>COUNTRY</u>	<u>APPLICATION NUMBER</u>	<u>MONTH/DAY/YEAR</u>
Japan	10-313976	October 16, 1998
Japan	11-092855	March 31, 1999
Japan	11-172024	June 18, 1999
Japan	11-242883	August 30, 1999

Certified copies of the corresponding Convention Application(s)

- ☐ are submitted herewith
- ☐ will be submitted prior to payment of the Final Fee
- ☒ were filed in prior application Serial No. 09/420,524 filed 10/18/99
- ☐ were submitted to the International Bureau in PCT Application Number
Receipt of the certified copies by the International Bureau in a timely manner under PCT Rule 17.1(a) has been acknowledged as evidenced by the attached PCT/IB/304.
- ☐ (A) Application Serial No.(s) were filed in prior application Serial No. filed ; and
- ☐ (B) Application Serial No.(s)
- ☐ are submitted herewith
- ☐ will be submitted prior to payment of the Final Fee

Respectfully Submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.



Norman F. Oblon
Registration No. 24,618



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240416US0DIV		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Masakazu KANECHIKA, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,444,244	08/95	Kirk et al.			
	AB	6,328,902	12/01	Hantschel et al.			
	AC	5,844,251	12/98	MacDonald et al.			
	AD	5,780,318	07/98	Hirano et al.			
	AE	5,587,588	12/96	Kim			
	AF	5,910,701	06/99	Takemura			
	AG	6,333,598	12/01	Hsu et al.			
	AH	6,066,265	05/00	Galvin et al.			
	AI	5,367,165	11/94	Toda et al.			
	AJ	4,968,585	11/90	Albrecht et al.			
	AK	4,933,058	06/90	Bache et al.			
	AL	6,201,401	03/01	Hellenmans et al.			
	AM	5,295,305	03/94	Hahn et al.			
	AN	5,614,663	03/97	Itoh et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	6-163481	06/10/94	Japan (w/English Abstract)			XX
	AP	9-260312	10/03/97	Japan (w/English Abstract)			XX
	AQ	8-250020	09/27/96	Japan (w/English Abstract)			XX
	AR	63-051641	03/04/88	Japan (w/English Abstract)			XX
	AS	10-188785	04/08/98	Japan (w/English Abstract, corr. to US 6,036,566)			XX
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Seigo KANEMARU, et al., "FABRICATION OF METAL-OXIDE-SEMICONDUCTOR FIELD-EFFECT-TRANSISTOR-STRUCTURED SILICON FIELD EMITTERS WITH A POLYSILICON DUAL GATE", Jpn. J. Appl. Phys., Vol. 36, Part 1, No. 12B, December 1997, pages 7736-7740					
	AX	Yoshikazu HORI, et al., "NEW SUB-MICORN SIZE Si FIELD EMITTER ARRAYS WITH LOW OPERATION VOLTAGE", technical Report of The Institute of Electronics Information and Communication Engineers, ED94-95, 1994-12, pages 1-8, (w/English Abstract)					
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240416US0DIV		SERIAL NO. New Application	
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				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,232,568	08/93	Parent et al.			
	AB	5,497,656	03/96	Kado et al.			
	AC	6,285,811	09/01	Aggarwal et al.			
	AD	6,132,942	10/00	Woodworth et al.			
	AE	6,227,519	05/01	Yagi et al.			
	AF	5,992,268	11/99	Decker et al.			
	AG	5,967,873	10/99	Rabinowitz			
	AH	6,270,950	08/01	Bourdels et al.			
	AI	6,036,566	03/14/00	Baldi et al.			
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner					Date Considered		
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